

# N-Channel Depletion-Mode MOSFET

#### **Ordering Information**

BV <sub>DSX</sub> /	R <sub>DS(ON)</sub>	I <sub>DSS</sub>	Order Number / Package TO-236AB*		
BV <sub>DGX</sub>	(max)	(min)			
500V	1.0KΩ	1.0mA	LND250K1		

Product marking for SOT-23:

NDE\*

where \* = 2-week alpha date code

#### **Features**

- ESD gate protection
- Free from secondary breakdown
- Low power drive requirement
- Ease of paralleling
- Excellent thermal stability
- Integral source-drain diode
- High input impedance and low C<sub>ISS</sub>

#### **Advanced DMOS Technology**

The LND2 is a high voltage N-channel depletion mode (normally-on) transistor utilizing Supertex's lateral DMOS technology. The gate is ESD protected.

The LND2 is ideal for high voltage applications in the areas of normally-on switches, precision constant current sources, voltage ramp generation and amplification.

## **Applications**

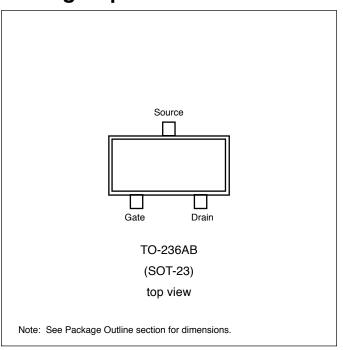
- Solid state relays
- Normally-on switches
- Converters
- Power supply circuits
- Constant current sources
- Input protection circuits

### **Absolute Maximum Ratings**

Drain-to-Source Voltage	$BV_{DSX}$
Drain-to-Gate Voltage	$BV_{DGX}$
Gate-to-Source Voltage	±20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

<sup>\*</sup> Distance of 1.6 mm from case for 10 seconds.

#### **Package Options**



#### 12/13/01

<sup>\*</sup>Same as SOT-23. All units shipped on 3,000 piece carrier tape reels.

#### **Thermal Characteristics**

Package	I <sub>D</sub> (continuous)*	I <sub>D</sub> (pulsed)	Power Dissipation @T <sub>A</sub> = 25°C	θ <sub>jc</sub> °C/W	θ <sub>ja</sub> °C/W	I <sub>DR</sub>	l_*
TO-236AB	13mA	30mA	0.36W	200	350	13mA	30mA

<sup>\*</sup> I<sub>D</sub> (continuous) is limited by max rated T<sub>r</sub>.

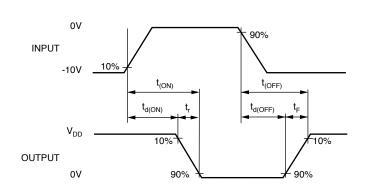
## Electrical Characteristics (@ 25°C unless otherwise specified)

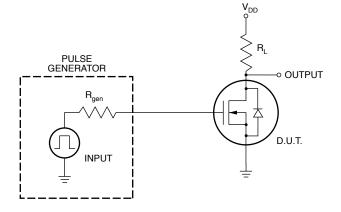
Symbol	Parameter	Min	Тур	Max	Unit	Conditions	
BV <sub>DSX</sub>	Drain-to-Source Breakdown Voltage	500			V	$V_{GS} = -10V, I_D = 1.0mA$	
V <sub>GS(OFF)</sub>	Gate-to-Source OFF Voltage	-1.0		-3.0	V	$V_{DS} = 25V, I_{D} = 100nA$	
$\Delta V_{GS(OFF)}$	Change in V <sub>GS(OFF)</sub> with Temperature			5.0	mV/°C	$V_{DS} = 25V, I_{D} = 100nA$	
I <sub>GSS</sub>	Gate Body Leakage Current			100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
I <sub>D(OFF)</sub>	Drain-to-Source Leakage Current			100	nA	V <sub>GS</sub> = -10V, V <sub>DS</sub> = 450V	
				100	μА	$V_{GS} = -10V$ , $V_{DS} = 0.8V$ max rating $T_A = 125$ °C	
I <sub>DSS</sub>	Saturated Drain-to-Source Current	1.0		3.0	mA	$V_{GS} = 0V, V_{DS} = 25V$	
R <sub>DS(ON)</sub>	Static Drain-to-Source ON-State Resistance		850	1K	Ω	$V_{GS} = 0V, I_{D} = 0.5mA$	
$\Delta R_{DS(ON)}$	Change in R <sub>DS(ON)</sub> with Temperature			1.2	%/°C	$V_{GS} = 0V, I_D = 0.5mA$	
G <sub>FS</sub>	Forward Transconductance	1.0	2.0		m &	$V_{GS} = 0V, I_{D} = 1.0mA$	
C <sub>ISS</sub>	Input Capacitance		7.5	10		$V_{GS} = -10V, V_{DS} = 25V$	
C <sub>OSS</sub>	Output Capacitance		2.0	3.5	pF	f = 1MHz	
C <sub>RSS</sub>	Reverse Transfer Capacitance		0.5	1.0			
t <sub>d(ON)</sub>	Turn-ON Delay Time		0.09			$V_{DD}$ = 25V, $I_D$ = 1.0mA, $R_{GEN}$ = 25 $\Omega$	
tr	Rise Time		0.45				
t <sub>d(OFF)</sub>	Turn-OFF Delay Time		0.1		μs		
t <sub>f</sub>	Fall Time		1.3				
V <sub>SD</sub>	Diode Forward Voltage Drop			0.9	V	V <sub>GS</sub> = -10V, I <sub>SD</sub> = 1.0mA	
t <sub>rr</sub>	Reverse Recovery Time		200		ns	$V_{GS} = -10V, I_{SD} = 1.0mA$	

#### Notes:

- 1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
- 2. All A.C. parameters sample tested.

## **Switching Waveforms and Test Circuit**





12/13/010